



TABLE 1. PIN DESCRIPTIONS

Number	Name	Type		Description
1, 48	V _{DD}	Power		Core supply pins.
2	CLK0	Input	Pulldown	LVCMOS / LVTTL clock input.
3	DIV_SELA	Input	Pullup	Controls frequency division for Bank A outputs. LVCMOS / LVTTL interface levels.
4	DIV_SELB	Input	Pullup	Controls frequency division for Bank B outputs. LVCMOS / LVTTL interface levels..
5	DIV_SELC	Input	Pullup	Controls frequency division for Bank C outputs. LVCMOS / LVTTL interface levels.
6	DIV_SELD	Input	Pullup	Controls frequency division for Bank D outputs. LVCMOS / LVTTL interface levels.
7	CLK_ENA	Input	Pullup	Output enable for Bank A outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS / LVTTL interface levels.
8	CLK_ENB	Input	Pullup	Output enable for Bank B outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS / LVTTL interface levels.
9	CLK_ENC	Input	Pullup	Output enable for Bank C outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS / LVTTL interface levels.
10	CLK_END	Input	Pullup	Output enable for Bank D outputs. Active HIGH. If pin is LOW, outputs drive low. LVCMOS / LVTTL interface levels.
11	nMR/OE	Input	Pullup	Master reset. When LOW, resets the ÷1/÷2 flip flops and sets the outputs to high impedance. LVCMOS / LVTTL interface levels.
12, 16, 20, 24, 28, 32, 36, 40, 44	GND	Power		Power supply ground.
13, 15, 17, 19	QD3, QD2, QD1, QD0	Output		Bank D outputs. LVCMOS / LVTTL interface levels.
14, 18	V _{DDOD}	Power		Output Bank D power supply pins.
21, 23, 25, 27	QC3, QC2, QC1, QC0	Output		Bank C outputs. LVCMOS / LVTTL interface levels.
22, 26	V _{DDOC}	Power		Output Bank C power supply pins.
29, 31, 33, 35	QB3, QB2, QB1, QB0	Output		Bank B outputs. LVCMOS / LVTTL interface levels.
30, 34	V _{DDOB}	Power		Output Bank B power supply pins.
37, 39, 41, 43	QA3, QA2, QA1, QA0	Output		Bank A outputs. LVCMOS / LVTTL interface levels.
38, 42	V _{DDOA}	Power		Output Bank A power supply pins.
45	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects CLK1, nCLK1 inputs. When LOW, selects CLK0 input. LVCMOS / LVTTL interface levels.
46	nCLK1	Input	Pullup	Inverting differential clock input.
47	CLK1	Input	Pulldown	Non-inverting differential clock input.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.



TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C_{IN}	Input Capacitance			4		pF
R_{PULLUP}	Input Pullup Resistor			51		K Ω
C_{PD}	Power Dissipation Capacitance (per output)	$V_{DD}, V_{DDOx} = 3.465V$; NOTE 1			18	pF
		$V_{DD} = 3.465, V_{DDOx} = 2.625V$; NOTE 1			20	pF
		$V_{DD} = 3.465, V_{DDOx} = 1.89V$; NOTE 1			30	pF
R_{OUT}	Output Impedance			7		Ω

NOTE 1: V_{DDOx} denotes $V_{DDOA}, V_{DDOB}, V_{DDOC},$ and V_{DDOD} .

TABLE 3. FUNCTION TABLE

Inputs			Outputs	
nMR/OE	CLK_ENx	DIV_SELx	Bank X	Qx Frequency
0	X	X	Hi Z	N/A
1	1	0	Active	fIN/2
1	1	1	Active	fIN
1	0	X	Low	N/A



ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5V$
Outputs, V_O	-0.5V to $V_{DDO} + 0.5V$
Package Thermal Impedance, θ_{JA}	47.9°C/W (0 lfpm)
Storage Temperature, T_{STG}	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 4A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Core Supply Voltage		3.135	3.3	3.465	V
V_{DDOx}	Output Supply Voltage; NOTE 1		3.135	3.3	3.465	V
			2.375	2.5	2.625	V
			1.71	1.8	1.89	V
I_{DD}	Power Supply Current				100	mA
I_{DDOx}	Output Supply Current; NOTE 2				15	mA

NOTE 1: V_{DDOx} denotes V_{DDOx} , V_{DDOx} , V_{DDOx} , and V_{DDOx} . NOTE 2: I_{DDOx} denotes I_{DDOx} , I_{DDOx} , I_{DDOx} , and I_{DDOx} .

TABLE 4B. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	DIV_SELA:DIV_SELd, CLK_ENA:CLK_END, nMR/OE, CLK_SEL	2		$V_{DD} + 0.3$	V
		CLK0	2		$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	DIV_SELA:DIV_SELd, CLK_ENA:CLK_END, nMR/OE, CLK_SEL	-0.3		0.8	V
		CLK0	-0.3		1.3	V
I_{IH}	Input High Current	CLK_ENA:CLK_END, DIV_SELA:DIV_SELd, nMR/OE	$V_{DD} = V_{IN} = 3.465V$		5	μA
		CLK0, CLK_SEL	$V_{DD} = V_{IN} = 3.465V$		150	μA
I_{IL}	Input Low Current	CLK_ENA:CLK_END, DIV_SELA:DIV_SELd, nMR/OE	$V_{DD} = 3.465V, V_{IN} = 0V$	-150		μA
		CLK0, CLK_SEL	$V_{DD} = 3.465V, V_{IN} = 0V$	-5		μA
V_{OH}	Output High Voltage; NOTE 1	$V_{DDOx} = 3.3V \pm 5\%$; NOTE 2	2.6			V
		$V_{DDOx} = 2.5V \pm 5\%$; NOTE 2	1.8			V
		$V_{DDOx} = 1.8V \pm 5\%$; NOTE 2 $I_{OH} = -2mA$	$V_{DD} - 0.45$			V
V_{OL}	Output Low Voltage; NOTE 1	$V_{DDOx} = 3.3V \pm 5\%$; NOTE 2			0.5	V
		$V_{DDOx} = 2.5V \pm 5\%$; NOTE 2			0.5	V
		$V_{DDOx} = 1.8V \pm 5\%$; NOTE 2 $I_{OL} = 2mA$			0.45	V
I_{OZL}	Output Tristate Current Low		-5			μA
I_{OZH}	Output Tristate Current High				5	μA

NOTE 1: Outputs terminated with 50Ω to $V_{DDOx}/2$. See Parameter Measurement Information, Output Load Test Circuit.

NOTE 2: V_{DDOx} denotes V_{DDOx} , V_{DDOx} , V_{DDOx} , and V_{DDOx} .



TABLE 4C. DIFFERENTIAL DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	nCLK1 $V_{IN} = V_{DD} = 3.465V$			5	μA
		CLK1 $V_{IN} = V_{DD} = 3.465V$			150	μA
I_{IL}	Input Low Current	nCLK1 $V_{IN} = 0V, V_{DD} = 3.465V$	-150			μA
		CLK1 $V_{IN} = 0V, V_{DD} = 3.465V$	-5			μA
V_{PP}	Peak-to-Peak Input Voltage		0.15		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2		GND + 0.5		$V_{DD} - 0.85$	V

NOTE 1: For single ended applications, the maximum input voltage for CLK1, nCLK1 is $V_{DD} + 0.3V$.

NOTE 2: Common mode voltage is defined as V_{IH} .

TABLE 5A. AC CHARACTERISTICS, $V_{DD} = V_{DDOX} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency				250	MHz
t_{pLH}	Propagation Delay, Low to High	CLK0; NOTE 1A	2.8	3.2	3.7	ns
		CLK1, nCLK1; NOTE 1B	2.9	3.4	3.9	ns
$t_{sk(b)}$	Bank Skew; NOTE 2, 7	Measured on the Rising Edge			30	ps
$t_{sk(o)}$	Output Skew; NOTE 3, 7	Measured on the Rising Edge			150	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 5, 7				750	ps
t_R / t_F	Output Rise/Fall Time; NOTE 6	20% to 80%	200		700	ps
odc	Output Duty Cycle	$f < 175MHz$	45		55	%
		$f \geq 175MHz$	40		60	%
t_{EN}	Output Enable Time; NOTE 6				10	ns
t_{DIS}	Output Disable Time; NOTE 6				10	ns

All parameters measured at 250MHz unless noted otherwise.

NOTE 1A: Measured from the $V_{DD}/2$ of the input to $V_{DDOX}/2$ of the output.

NOTE 1B: Measured from the differential input crossing point to $V_{DDOX}/2$ of the output.

NOTE 2: Defined as skew within a bank with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at $V_{DDOX}/2$.

NOTE 4: Defined as skew across banks of outputs switching in the same direction operating at different frequencies with the same supply voltages and equal load conditions. Measured at $V_{DDOX}/2$.

NOTE 5: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDOX}/2$.

NOTE 6: These parameters are guaranteed by characterization. Not tested in production.

NOTE 7: This parameter is defined in accordance with JEDEC Standard 65.



TABLE 5B. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDOX} = 2.5V \pm 5\%$, $T_A = 0^\circ C$ TO $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency				250	MHz
$t_{p_{LH}}$	Propagation Delay, Low to High	CLK0; NOTE 1A	2.9	3.3	3.8	ns
		CLK1, nCLK1; NOTE 1B	3	3.5	4	ns
$t_{sk(b)}$	Bank Skew; NOTE 2, 7	Measured on the Rising Edge			30	ps
$t_{sk(o)}$	Output Skew; NOTE 3, 7	Measured on the Rising Edge			160	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 5, 7				750	ps
t_R / t_F	Output Rise/Fall Time; NOTE 6	20% to 80%	200		700	ps
odc	Output Duty Cycle	$f < 175\text{MHz}$	45		55	%
		$f \geq 175\text{MHz}$	40		60	%
t_{EN}	Output Enable Time; NOTE 6				10	ns
t_{DIS}	Output Disable Time; NOTE 6				10	ns

All parameters measured at 250MHz unless noted otherwise.

NOTE 1A: Measured from the $V_{DD}/2$ of the input to $V_{DDOX}/2$ of the output.

NOTE 1B: Measured from the differential input crossing point to $V_{DDOX}/2$ of the output.

NOTE 2: Defined as skew within a bank with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at $V_{DDOX}/2$.

NOTE 4: Defined as skew across banks of outputs switching in the same direction operating at different frequencies with the same supply voltages and equal load conditions. Measured at $V_{DDOX}/2$.

NOTE 5: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDOX}/2$.

NOTE 6: These parameters are guaranteed by characterization. Not tested in production.

NOTE 7: This parameter is defined in accordance with JEDEC Standard 65.



TABLE 5C. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDOX} = 1.8V \pm 5\%$, $T_A = 0^\circ C$ TO $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency				250	MHz
tp_{LH}	Propagation Delay, Low to High	CLK0; NOTE 1A	3.1	3.8	4.5	ns
		CLK1, nCLK1; NOTE 1B	3.1	3.8	4.5	ns
$tsk(b)$	Bank Skew; NOTE 2, 7	Measured on the Rising Edge			30	ps
$tsk(o)$	Output Skew; NOTE 3, 7	Measured on the Rising Edge			170	ps
$tsk(pp)$	Part-to-Part Skew; NOTE 5, 7				750	ps
t_R / t_F	Output Rise/Fall Time; NOTE 6	20% to 80%	200		700	ps
odc	Output Duty Cycle	$f < 175MHz$	45		55	%
		$f \geq 175MHz$	40		60	%
t_{EN}	Output Enable Time; NOTE 6				10	ns
t_{DIS}	Output Disable Time; NOTE 6				10	ns

All parameters measured at 250MHz unless noted otherwise.

NOTE 1A: Measured from the $V_{DD}/2$ of the input to $V_{DDOX}/2$ of the output.

NOTE 1B: Measured from the differential input crossing point to $V_{DDOX}/2$ of the output.

NOTE 2: Defined as skew within a bank with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at $V_{DDOX}/2$.

NOTE 4: Defined as skew across banks of outputs switching in the same direction operating at different frequencies with the same supply voltages and equal load conditions. Measured at $V_{DDOX}/2$.

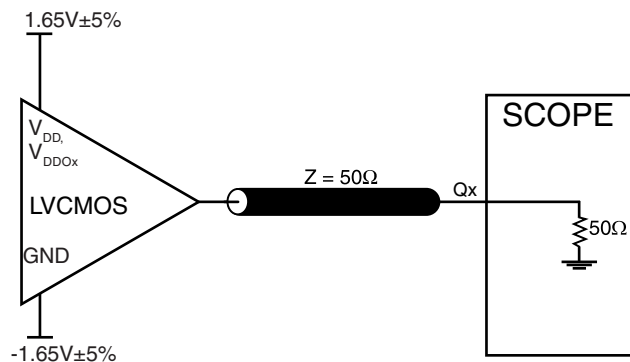
NOTE 5: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDOX}/2$.

NOTE 6: These parameters are guaranteed by characterization. Not tested in production.

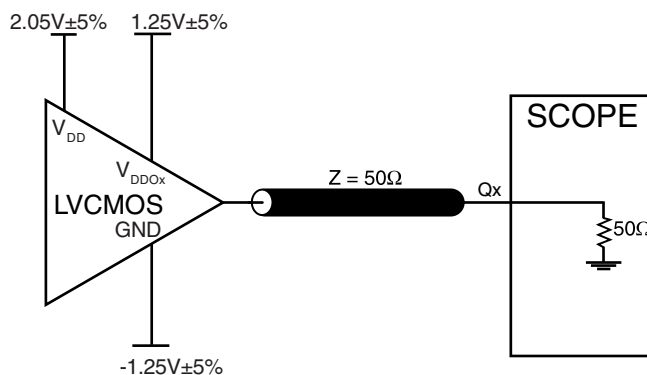
NOTE 7: This parameter is defined in accordance with JEDEC Standard 65.



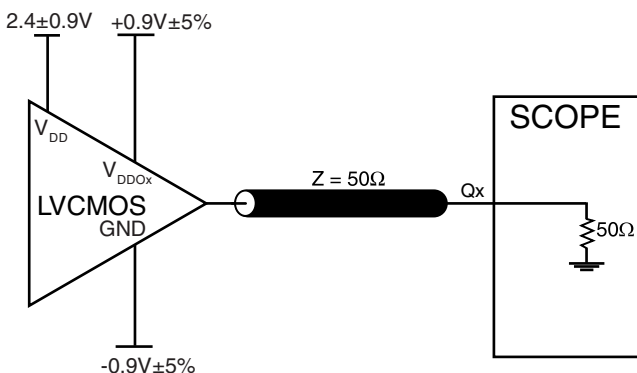
PARAMETER MEASUREMENT INFORMATION



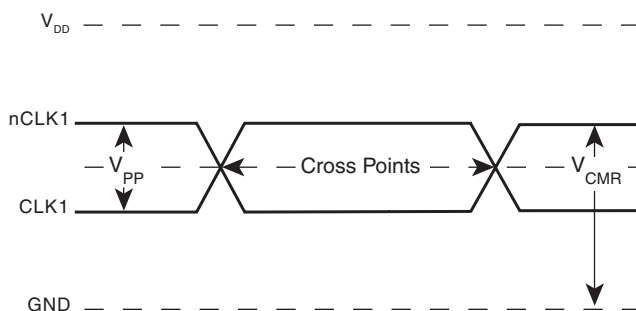
3.3V OUTPUT LOAD AC TEST CIRCUIT



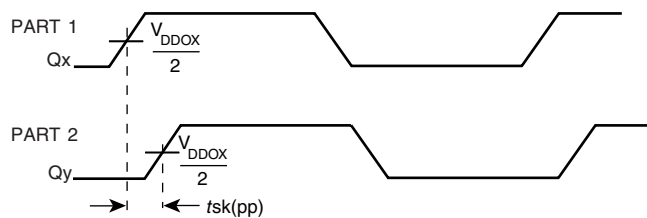
3.3V/2.5V OUTPUT LOAD AC TEST CIRCUIT



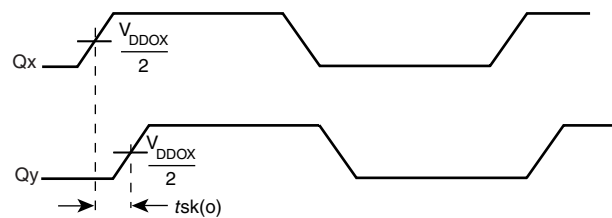
3.3V/1.8V OUTPUT LOAD AC TEST CIRCUIT



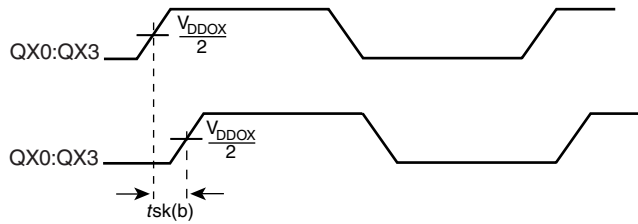
DIFFERENTIAL INPUT LEVEL



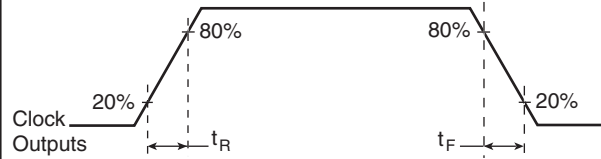
PART-TO-PART SKEW



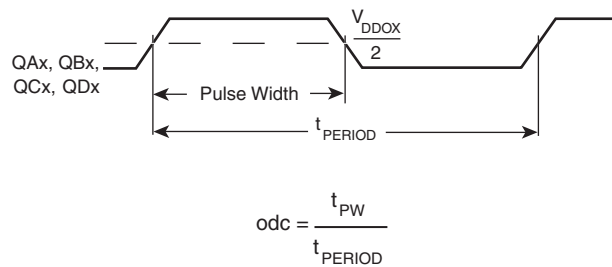
OUTPUT SKEW



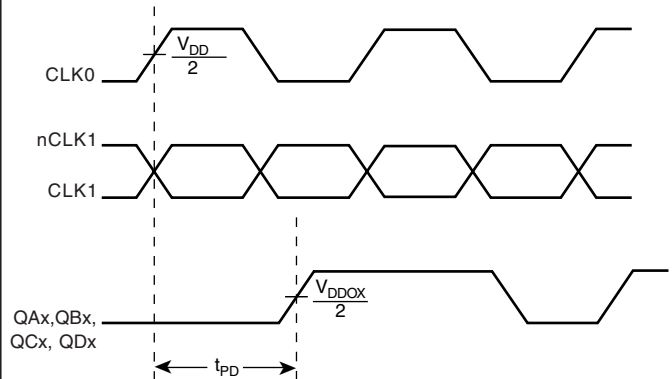
BANK SKEW (where X denotes outputs in the same bank)



OUTPUT RISE/FALL TIME



OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD



PROPAGATION DELAY



APPLICATION INFORMATION

WIRING THE DIFFERENTIAL INPUT TO ACCEPT SINGLE ENDED LEVELS

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage $V_{REF} = V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio

of R1 and R2 might need to be adjusted to position the V_{REF} in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_{REF} should be 1.25V and $R2/R1 = 0.609$.

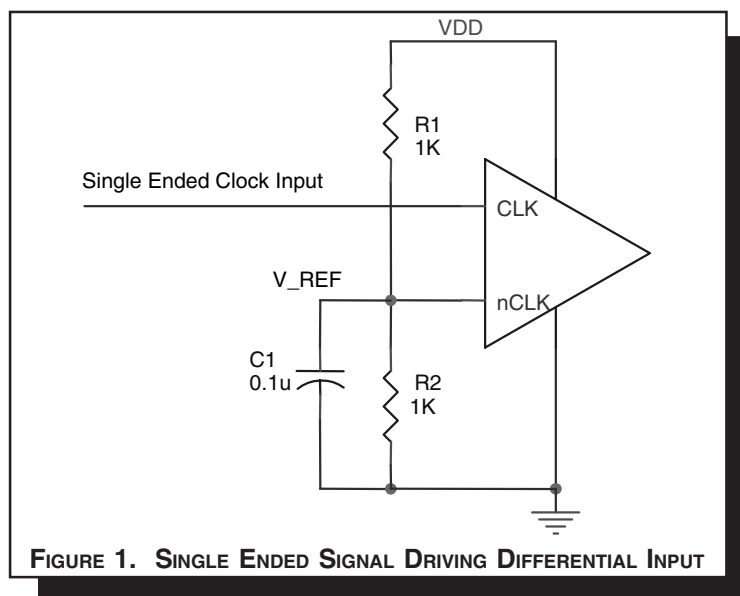


FIGURE 1. SINGLE ENDED SIGNAL DRIVING DIFFERENTIAL INPUT



DIFFERENTIAL CLOCK INPUT INTERFACE

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both V_{SWING} and V_{OH} must meet the V_{PP} and V_{CMR} input requirements. Figures 4A to 4E show interface examples for the HiPerClockS CLK/nCLK input driven by the most common driver types. The input interfaces suggested

here are examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example in *Figure 2A*, the input termination applies for ICS HiPerClockS LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

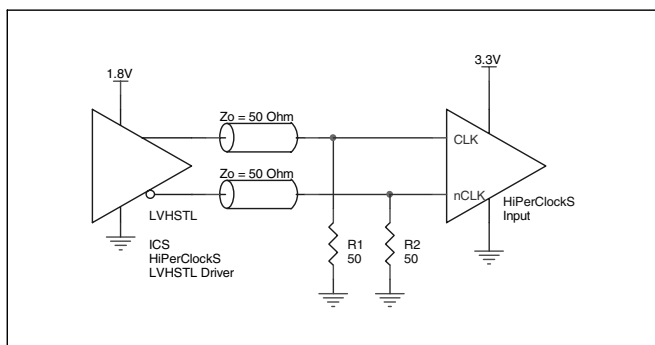


FIGURE 2A. HiPerClockS CLK/nCLK INPUT DRIVEN BY ICS HiPerClockS LVHSTL DRIVER

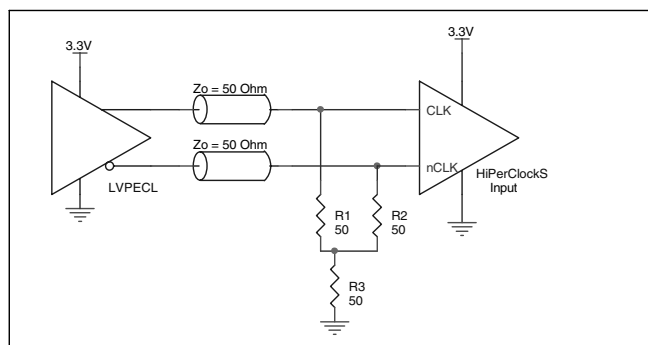


FIGURE 2B. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER

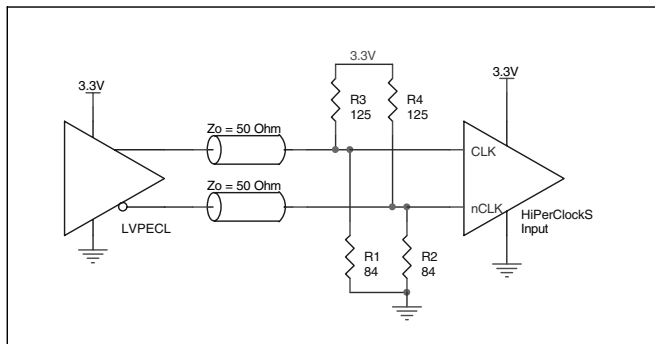


FIGURE 2C. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER

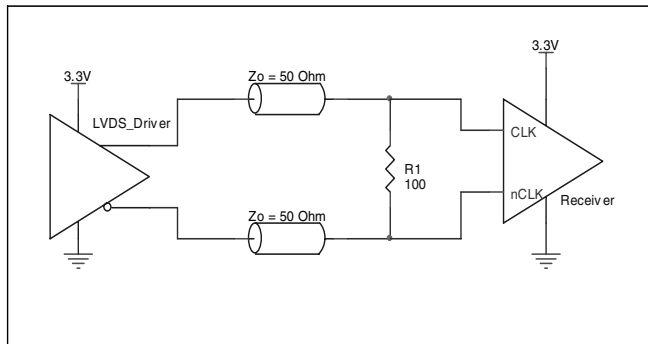


FIGURE 2D. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVDS DRIVER

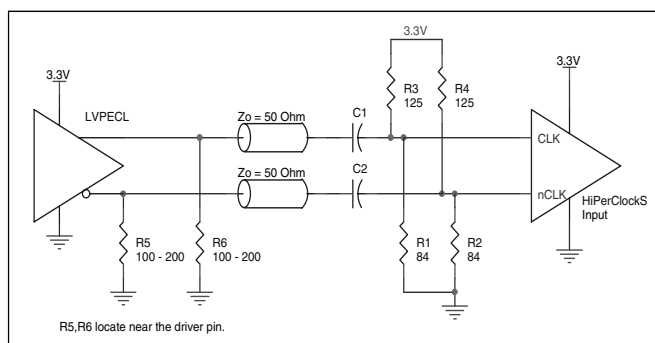


FIGURE 2E. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER WITH AC COUPLE



SCHEMATIC EXAMPLE

Figure 3 shows an application schematic example of the ICS87016. This schematic provides examples of input and output handling. The differential CLK1/nCLK1 input can accept various types of differential signal. This example shows the ICS87016 input driven by a 3.3V LVPECL driver. Additional examples for the input driven by other types of drivers

are shown in the application section of this data sheet. The single ended input CLK0 is driven by a 7Ω LVCMOS driver through series termination. The ICS87016 outputs are LVCMOS drivers. Series termination is shown in this schematic. Additional LVCMOS termination approaches are shown in the LVCMOS Termination Application Note.

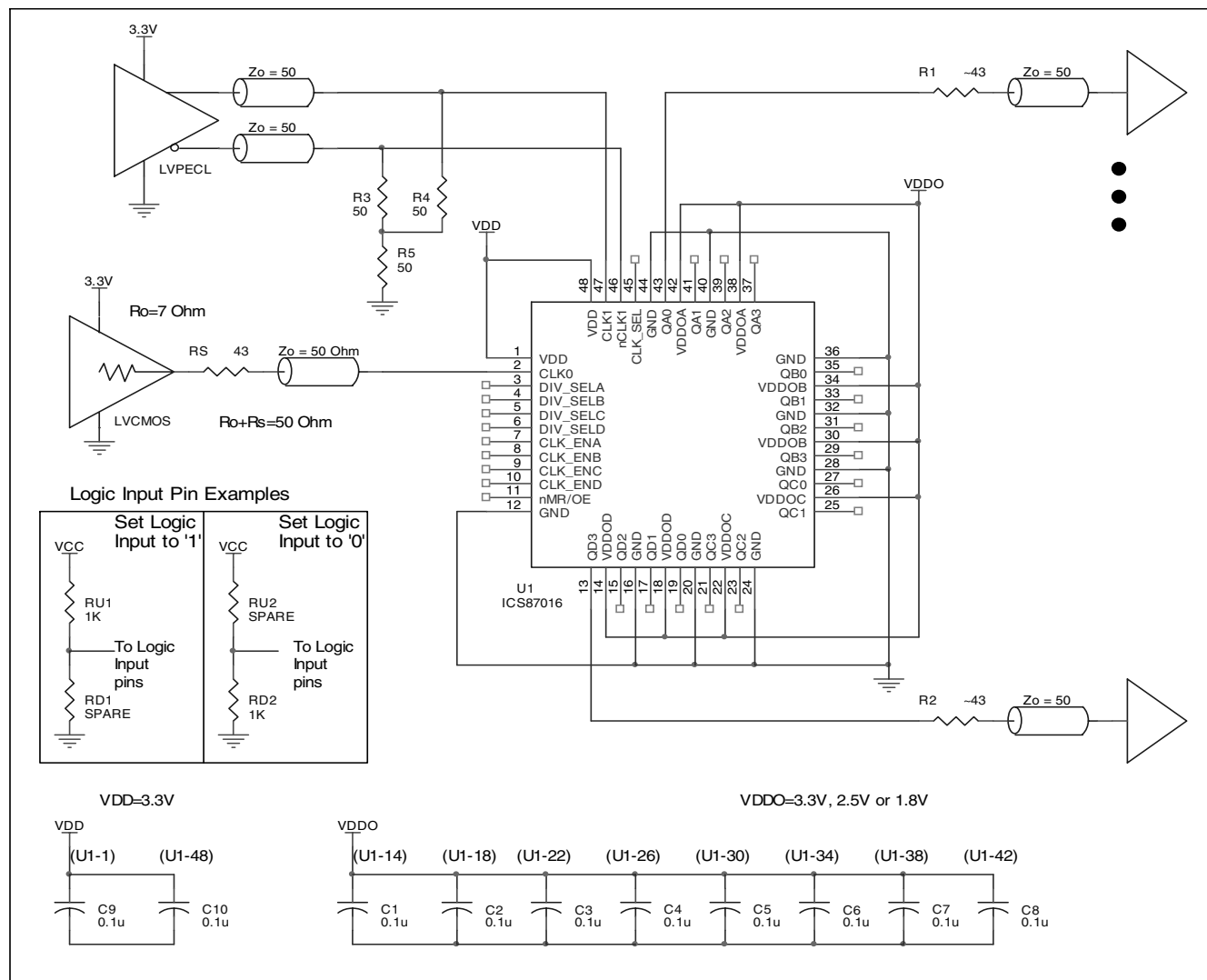


FIGURE 3. APPLICATION SCHEMATIC EXAMPLE



RELIABILITY INFORMATION

TABLE 6. θ_{JA} VS. AIR FLOW TABLE FOR 48 LEAD LQFP

θ_{JA} by Velocity (Linear Feet per Minute)			
	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	67.8°C/W	55.9°C/W	50.1°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	47.9°C/W	42.1°C/W	39.4°C/W
NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.			

TRANSISTOR COUNT

The transistor count for ICS87016 is: 2034



PACKAGE OUTLINE - Y SUFFIX FOR 48 LEAD LQFP

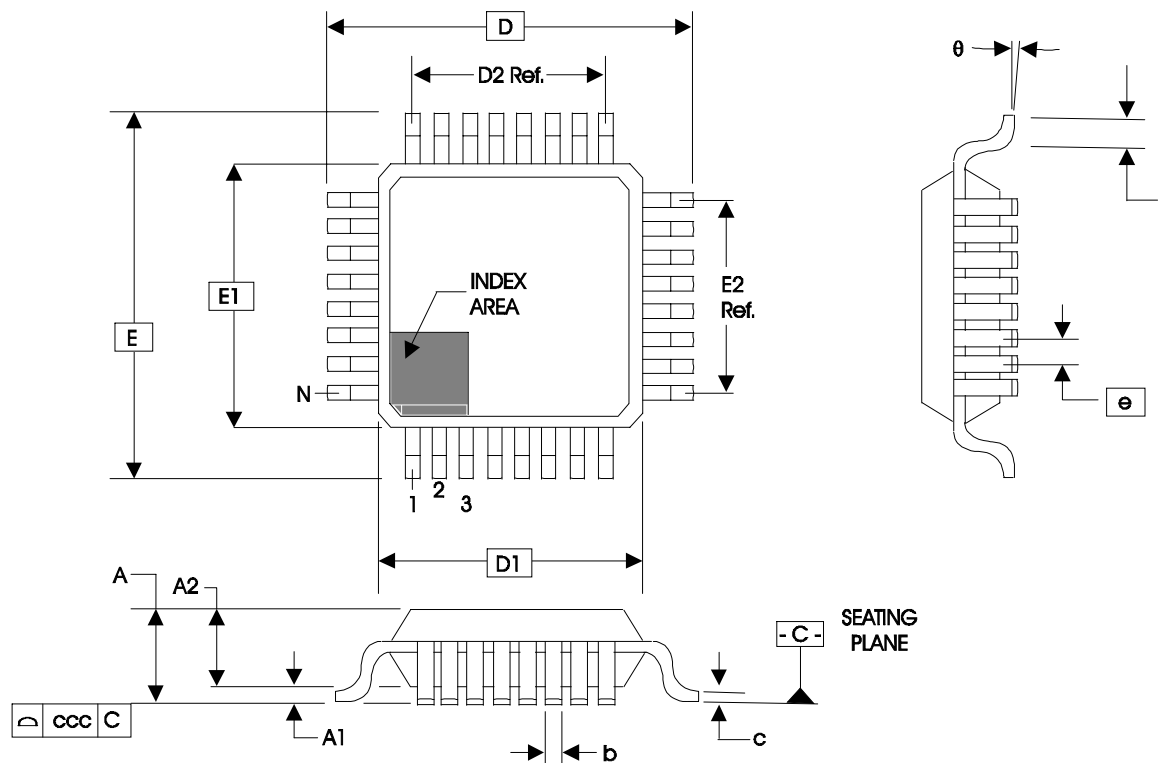


TABLE 7. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS			
SYMBOL	BBC		
	MINIMUM	NOMINAL	MAXIMUM
N	48		
A	--	--	1.60
A1	0.05	--	0.15
A2	1.35	1.40	1.45
b	0.17	0.22	0.27
c	0.09	--	0.20
D	9.00 BASIC		
D1	7.00 BASIC		
D2	5.50 Ref.		
E	9.00 BASIC		
E1	7.00 BASIC		
E2	5.50 Ref.		
e	0.50 BASIC		
L	0.45	0.60	0.75
θ	0°	--	7°
ccc	--	--	0.08

Reference Document: JEDEC Publication 95, MS-026



Integrated
Circuit
Systems, Inc.

ICS87016

Low SKEW, 1-TO-16

LVCMOS/LVTTL CLOCK GENERATOR

TABLE 8. ORDERING INFORMATION

Part/Order Number	Marking	Package	Count	Temperature
ICS87016AY	ICS87016AY	48 Lead LQFP	250 per tray	0°C to 85°C
ICS87016AYT	ICS87016AY	48 Lead LQFP on Tape and Reel	1000	0°C to 85°C

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Integrated
Circuit
Systems, Inc.

ICS87016
LOW SKEW, 1-TO-16
LVC MOS/LVTTL CLOCK GENERATOR

REVISION HISTORY SHEET				
Rev	Table	Page	Description of Change	Date
A	T5A, T5B, T5C	6, 7, 8	AC Characteristics Table - corrected the first line in the Notes section, from "All parameters measured at 150MHz..." to 250MHz.	7/31/02
A			Revised part description title from "Differential-to-LVC MOS Clock Generator" to "LVC MOS Clock Generator".	8/9/02
A	T5A & T5B	6 & 7 12	AC Characteristics Table - switched prop delay values for CLK0 and CLK1, nCLK1. Added Differential Clock Input Interface section. Updated format.	5/05/03
A		1	Modified Block Diagram, corrected latch block.	6/4/03
A		12	Added Schematic Example	12/10/04